


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/685,080	AHMED ET AL.	
	Examiner	Art Unit	
	Tae H. Yoon	1714	

SEARCHED			
Class	Subclass	Date	Examiner
523	130		
524	032		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
523	130	9-23-06	h

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	8-13-06	m
Inventor Search	6-15-06	n
EAST	9-23-06	g